Search Notes



Application/Control No.	App Ree:
10/724,173	HAN
Examiner	Art I

Applicant(s)/Patent under Reexamination	
HAMON ET AL.	
Art Unit	
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	Edward M. Johnson
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Class	Subclass	Date	Examiner
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502	74		
	338		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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	DATE	EXMR
Inventor name search	3/6/2006	EJ
EAST search in file		